



« Safe (hardware) design methodologies against fault attacks »

Bruno ROBISSON

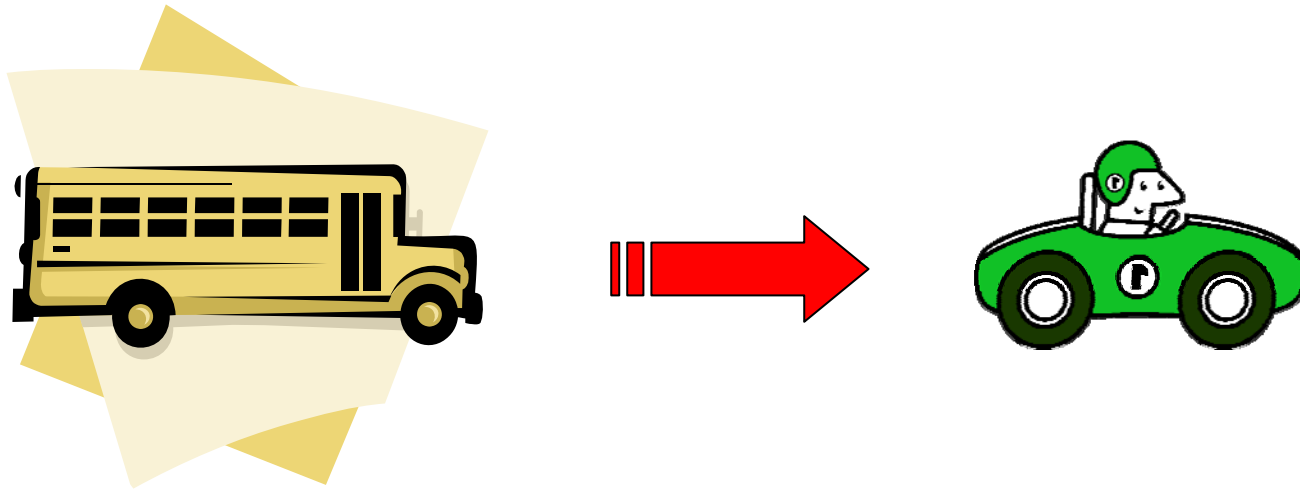
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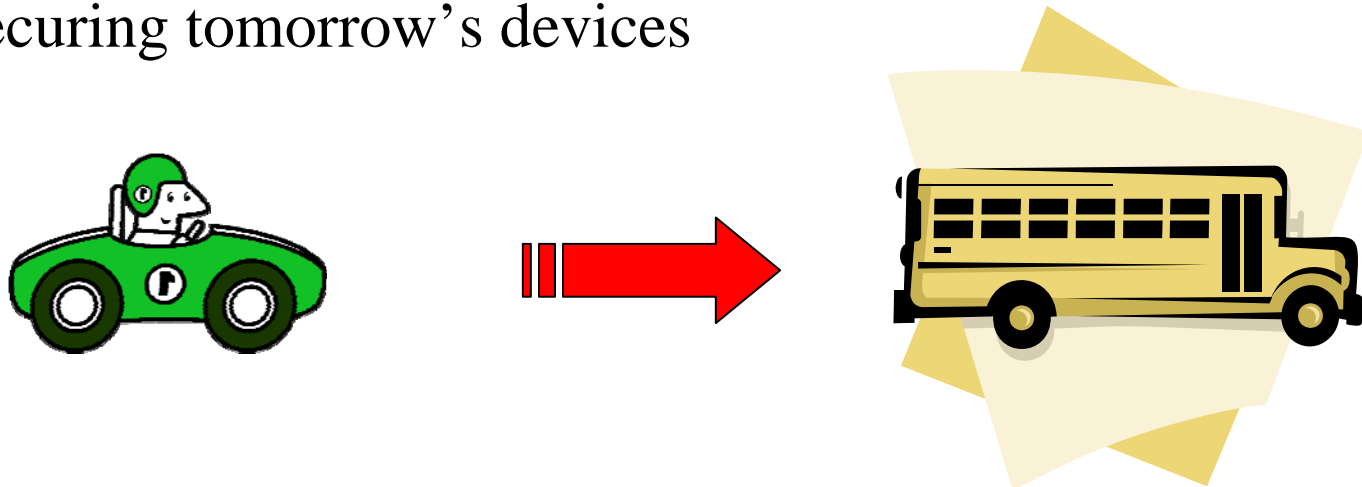
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Securing today's devices



Securing tomorrow's devices

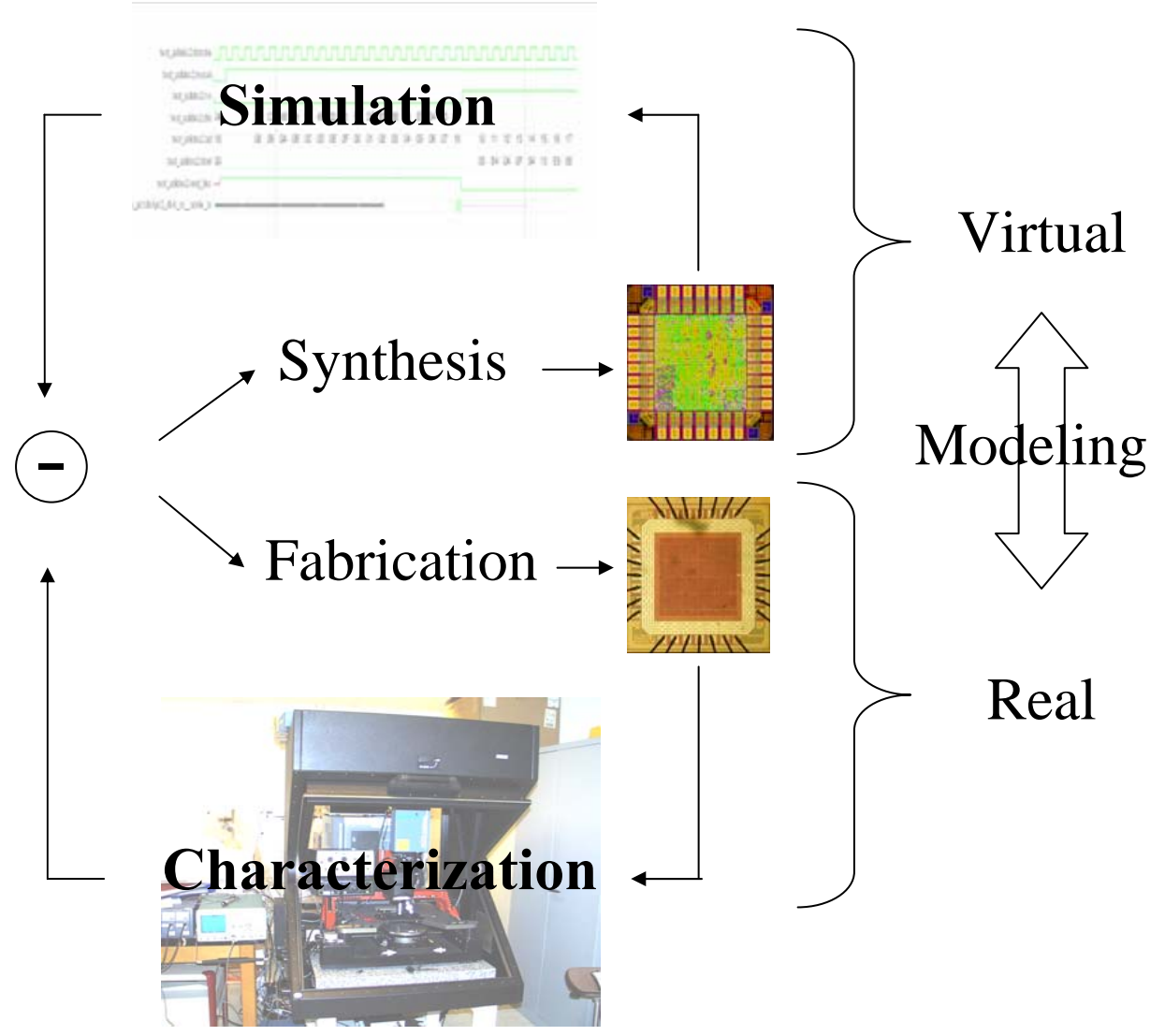


Specifications:

- ✓ Fonctionnalité
- ✓ Power,
- ✓ Speed,
- ✓ Price

Technology:

- ✓ CMOS
- ✓ SOI
- ✓ Molecular
- ✓ ...

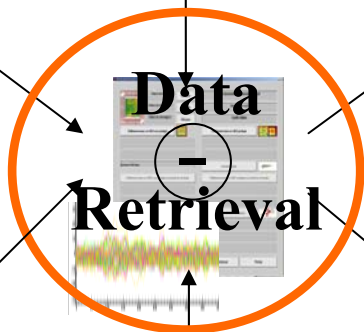


➔ How to secure devices to known attacks?

Specifications:

X - resistance

Technology



Simulation

Synthesis

Fabrication

Characterization

Syndroms

DFA and DPA test benches

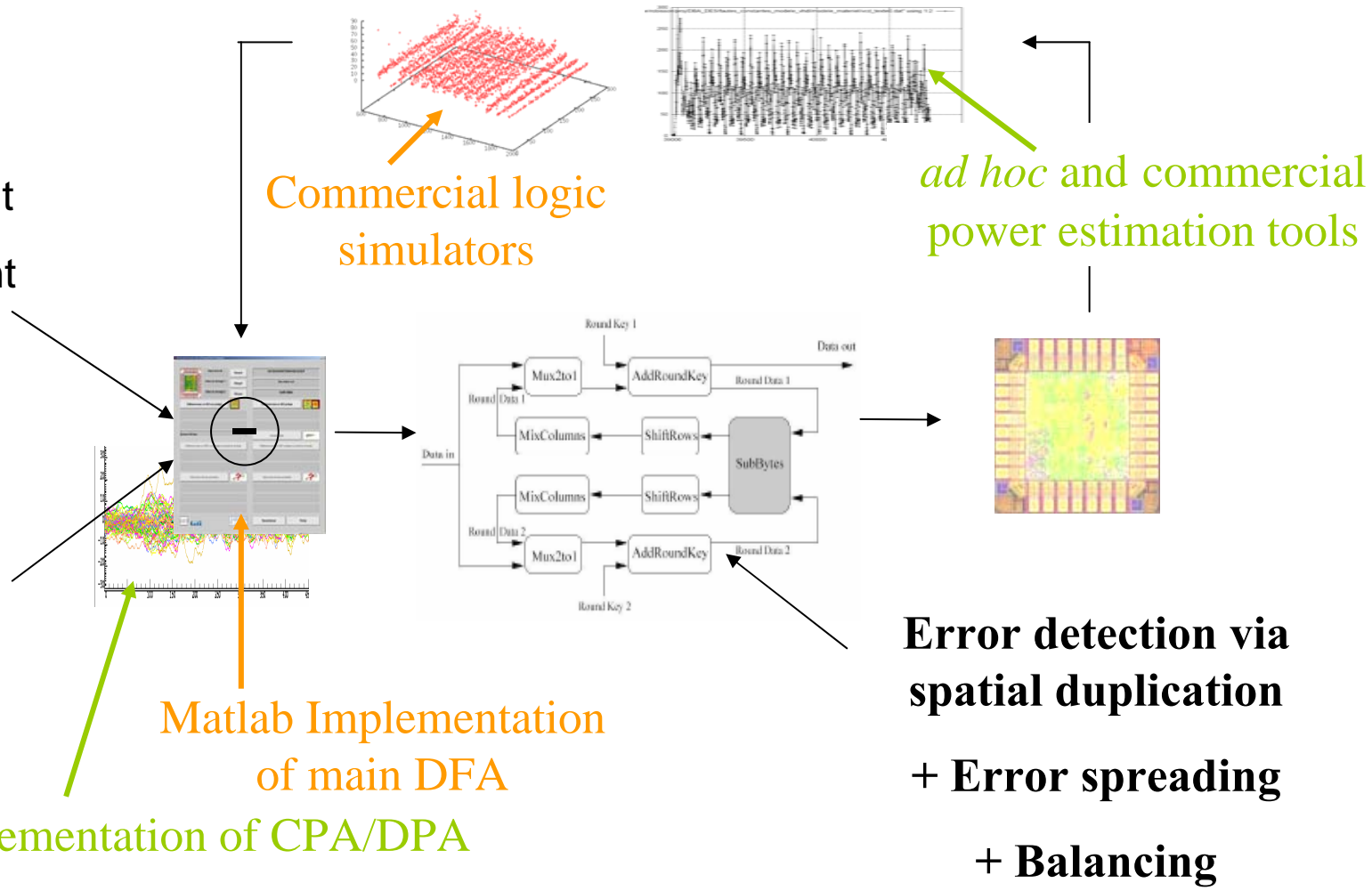
Example: Securing AES against DFA

Specifications:

- DFA-resistant
- DPA-resistant

Technology:

- CMOS

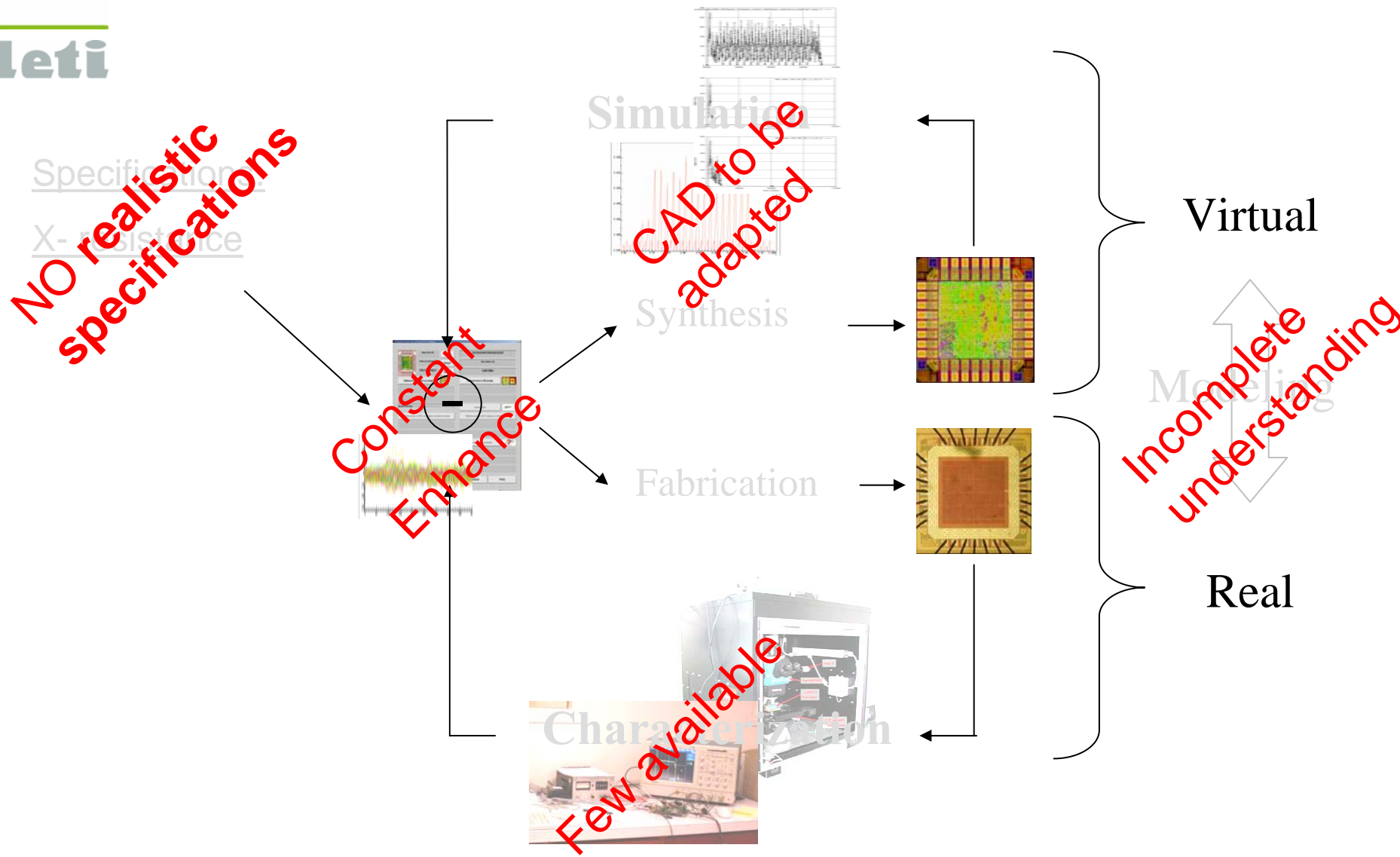


C Implementation of CPA/DPA

➡ Counter-measures validated

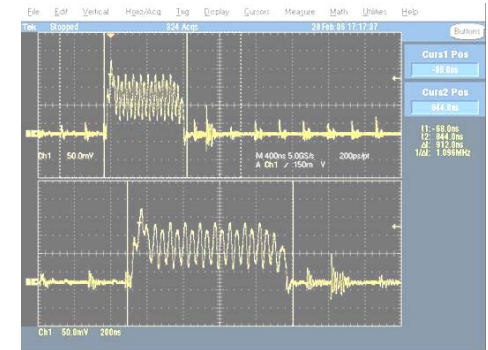
➡ Detecting sensitivity to round reduction attacks

Securing today's devices : the challenges



➤ Characterization

- Sharing equipments
- Publications should describe experimental protocols and equipments
- Towards an *a minima* standardization of security measurements (devoted to R&D's activities)

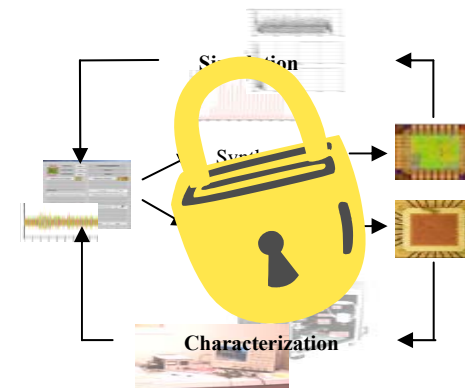


➤ Physics of attacks

- Modeling physical phenomena which make attacks possible (faults, EM)
- Dedicated test IC

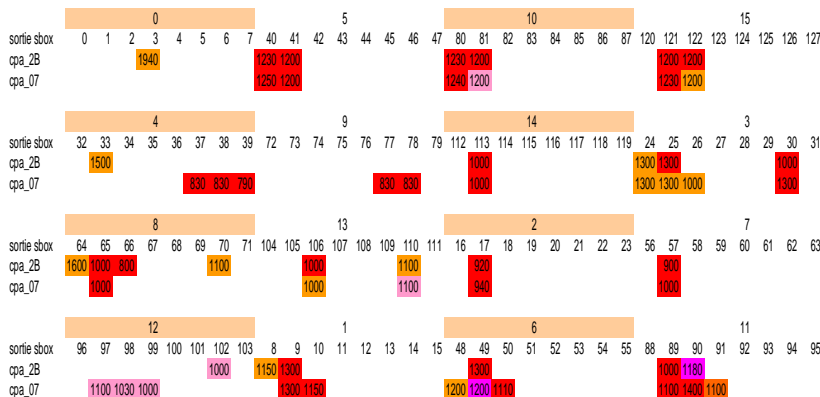
➤ CAD tools to be adapted (simulation and synthesis)

- Simulators should support models dedicated to security
- Development of *ad hoc* verification tools (based on formal methods)
- Formalization of security constraints
- Towards automatic synthesis of circuits verifying such constraints



➤ Data retrieval

- Data base of physical signals (power and EM waveforms, faulty executions traces)
- Challenges from this data base to improve data retrieval algorithms
- Open library of optimized cryptographic primitives (DPA, DFA and cryptanalysis)

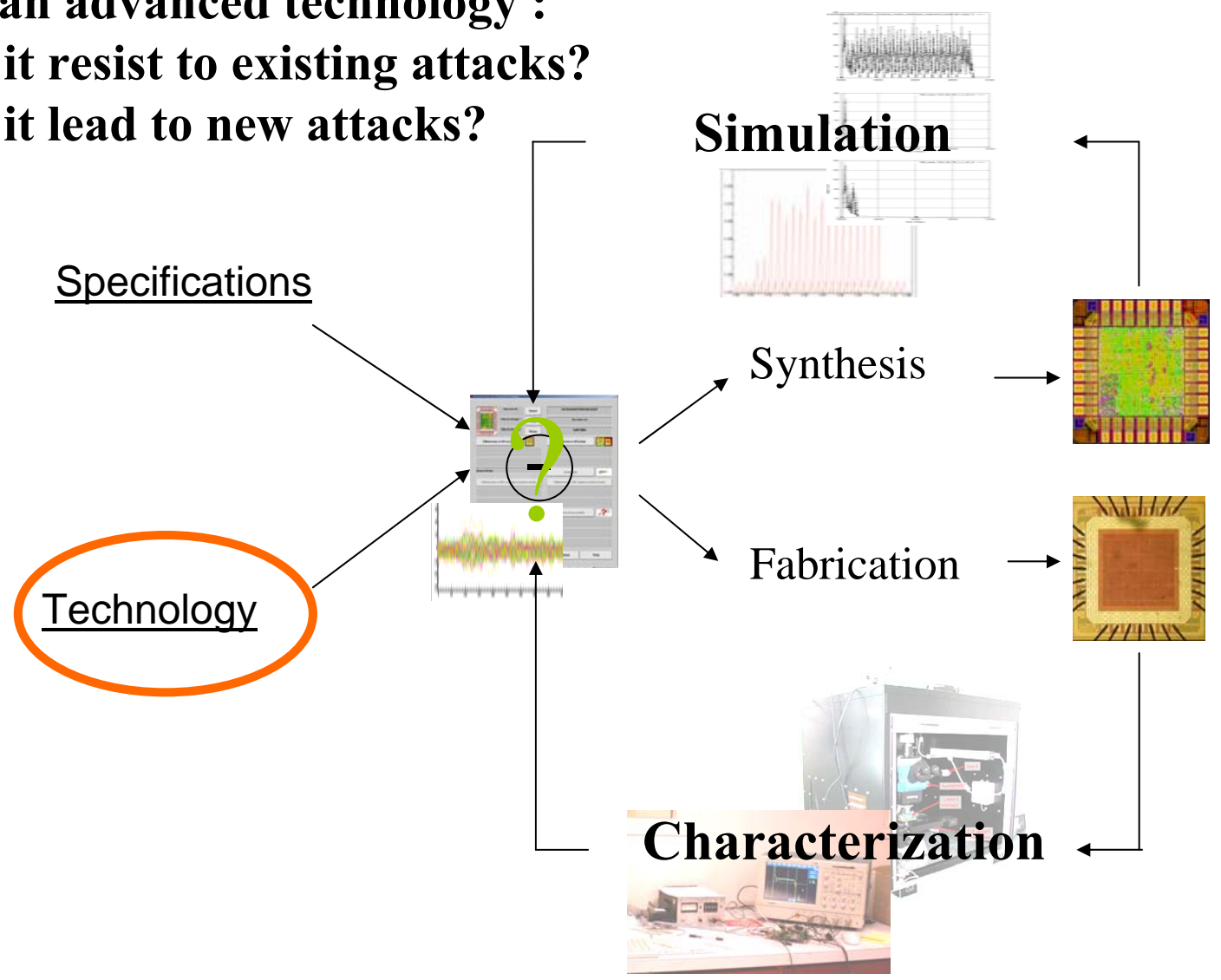


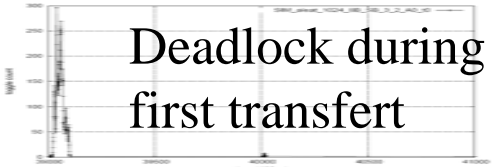
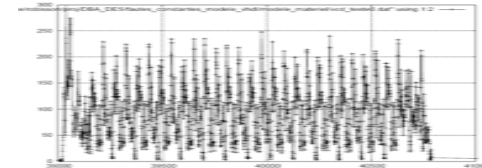
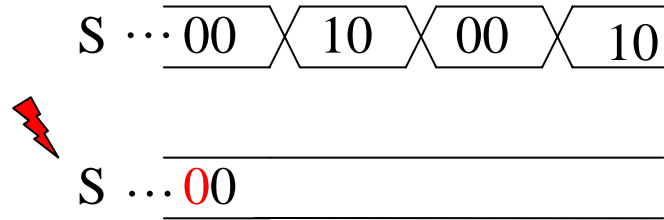
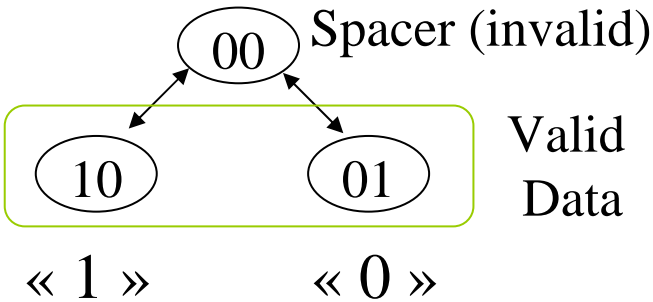
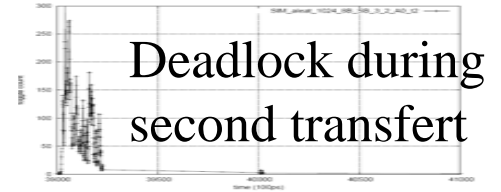
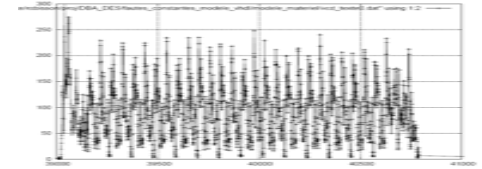
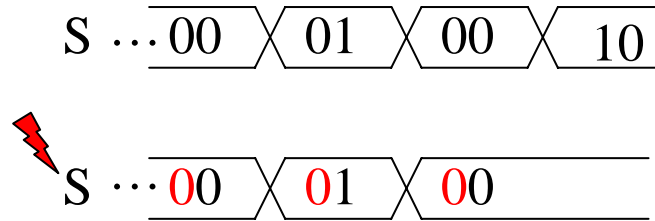
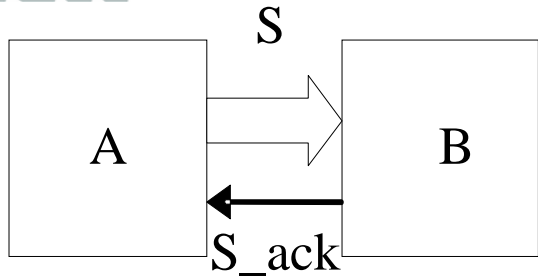
➤ Specifications

- Take care of « naive » counter-measures
- Take into account all the known attacks
- Always test counter-measures on real devices



- Given an advanced technology :**
- Will it resist to existing attacks?
 - Will it lead to new attacks?





- ➔ Permanent « stuck-at zero » on a wire of a dual rail may induce deadlock
- ➔ Deadlock instants depend on the data values
- ➔ Deadlock instants may be easily detected by monitoring the power consumption

Safe-error Key bits leak only through the information whether the device has a normal **behavior** or not in presence of fault

+ DPA **Correlating** a power model parameterized by the value of a small number of bits of the key (the partial key) to power measurements

Differential Behavioral Analysis

Correlating a functional model parameterized by the value of a partial key to **behaviors** of the device in presence of faults

DBA hypothesis

➤ DPA hypothesis

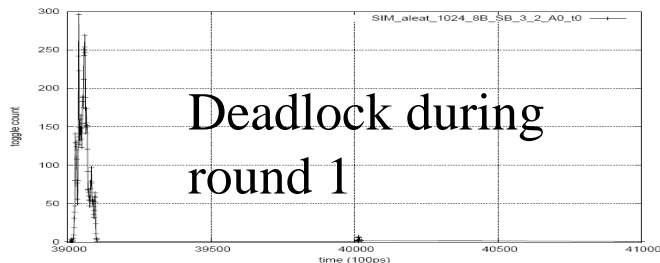
- Known cryptographic algorithms,
- Known plain texts (or cipher texts)
- There must exist intermediate variables that can be expressed as functions depending on the plain texts and on only a small number of key bits

➤ Fault injection

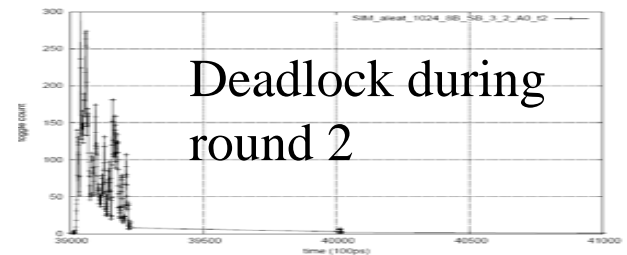
- Type : Stuck-at zero (or one)
- Location : On one bit in the set of the attack bits defined in DPA
- Duration : Permanent (or transient)
- Repetitivity : Same fault, at same time, on same bit

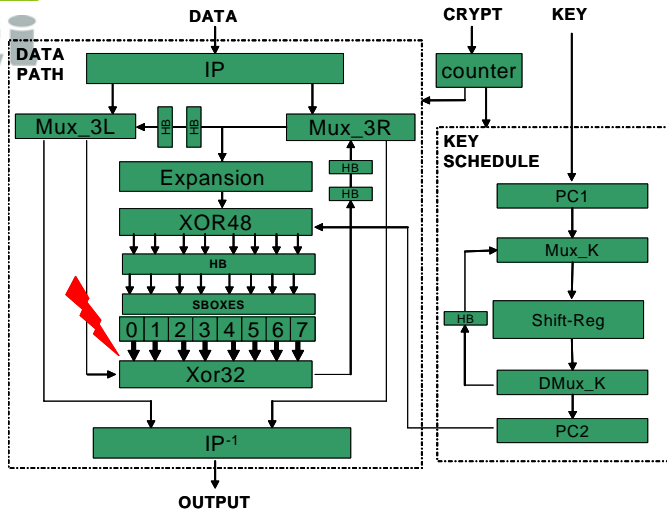


➤ Detecting behavior between faults which create an error during round one or during another round



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QDI asynchronous DES

Design

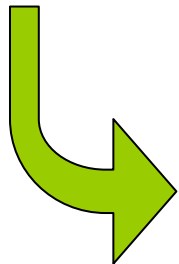
DPA counter-measures (logical balancing)

Standard cells

0.13 μm STMicroelectronics

180 ns for DES encryption

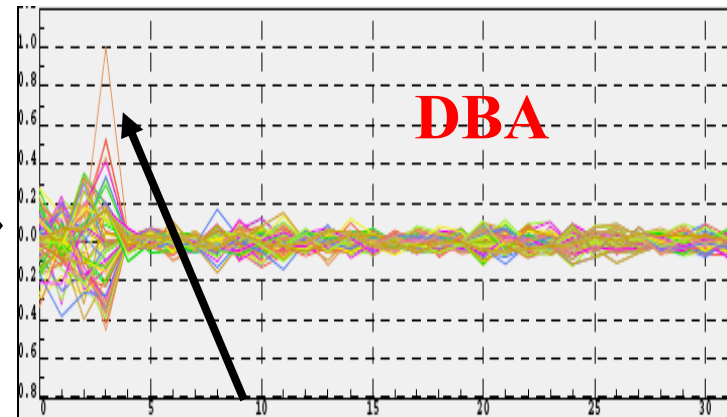
0.94mm² with interfaces



Faults injected on a bit at the output of the Sboxes

15 faulty executions with random values but known plain texts

Simulation



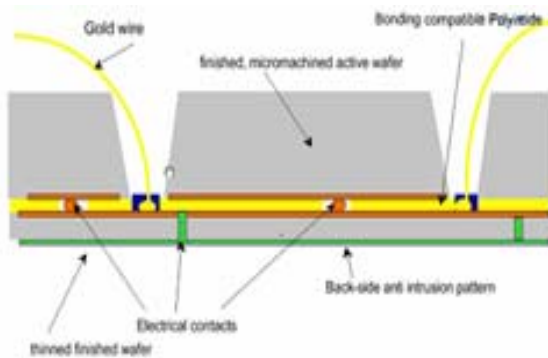
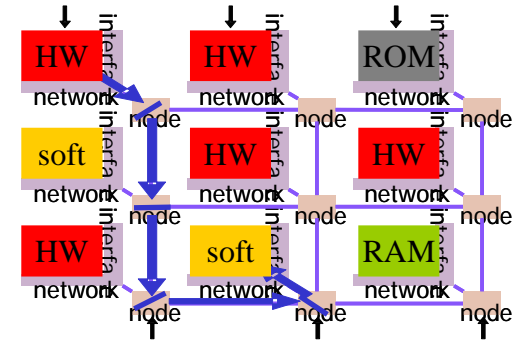
Value of the partial key (6 bit long)

Location of the faulty bit

Value of the faulty bit

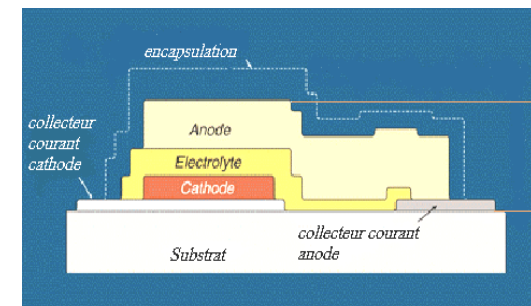
Repetitivity of the fault injection

- Evaluate advanced architectures
 - Asynchronous circuits, GALS
 - Reconfigurable devices
 - SOC, NOC
 - ...

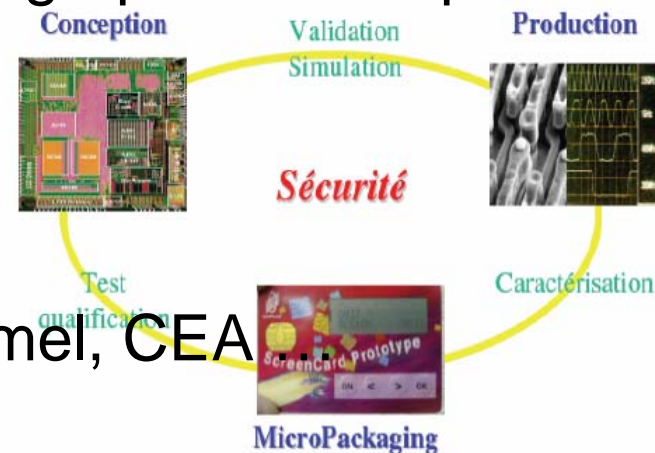


- Evaluate advanced technologies
 - SOI
 - Memories MRAM
 - Technology shrinking
 - Nano-technologies
 - Above-IC power sources
 - Smart packaging
 - ...

- Anticipate attacker's means
 - Equipments
 - Towards hybrid attacks



- A lot of work...
- Towards a more collaborative approach
 - Sharing some competences and equipments
 - Objective comparison of counter-measures
- But with incorporate industrial constraints
 - Fears and secrets around cryptographic developments
 - Time and cost constraints



CIMPACA/ Micro-Packs

- Gemalto, STMicroelectronics, Atmel, CEA
- LIRMM, ENST, ENSMSE,...